

Phonon-Only Events and Correlated Quasiparticle Poisoning

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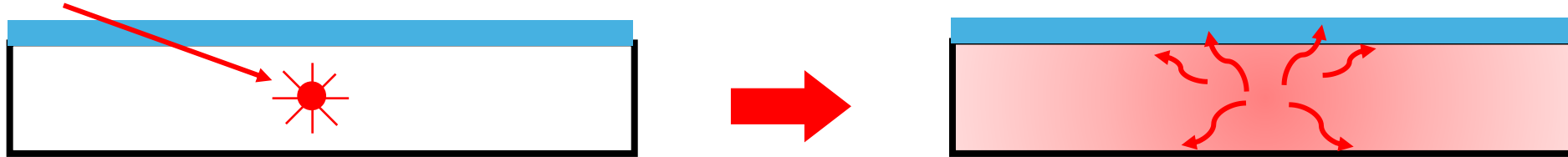
June 16, 2026



Phonon-mediated quasiparticle poisoning from radiation impacts

γ -ray, muon impact deposits $\sim 100 \text{ keV} - 1 \text{ MeV}$

rate $\sim 1/(10 \text{ s})$ for $(8 \text{ mm})^2$ chip



1. Generation of electron-hole pairs in Si, **offset charge jumps**
2. e-h recombination and radiation of high-energy phonons
3. **Pair-breaking phonons** travel throughout chip
4. Phonons impacting superconductor break pairs, quasiparticles recombine and emit 2Δ phonons back into Si.

→ Correlated pair-breaking & **quasiparticle** generation across the chip

Vepsäläinen *et al.*, Nature **584**, 551 (2020)

McEwen *et al.*, Nature Physics **18**, 107 (2021)

Wilen *et al.*, Nature **594**, 7863 (2021)

Martinis, npj Quantum **7**, 1 (2021)

Cardani *et al.*, Nature Comm. **12**, 1 (2021)

Iaia, Ku *et al.*, Nature Comm. **13**, 6425 (2022)

Thorbeck *et al.*, PRX Quantum **4**, 020356 (2023)



Signatures of phonon-mediated QP poisoning from particle impacts

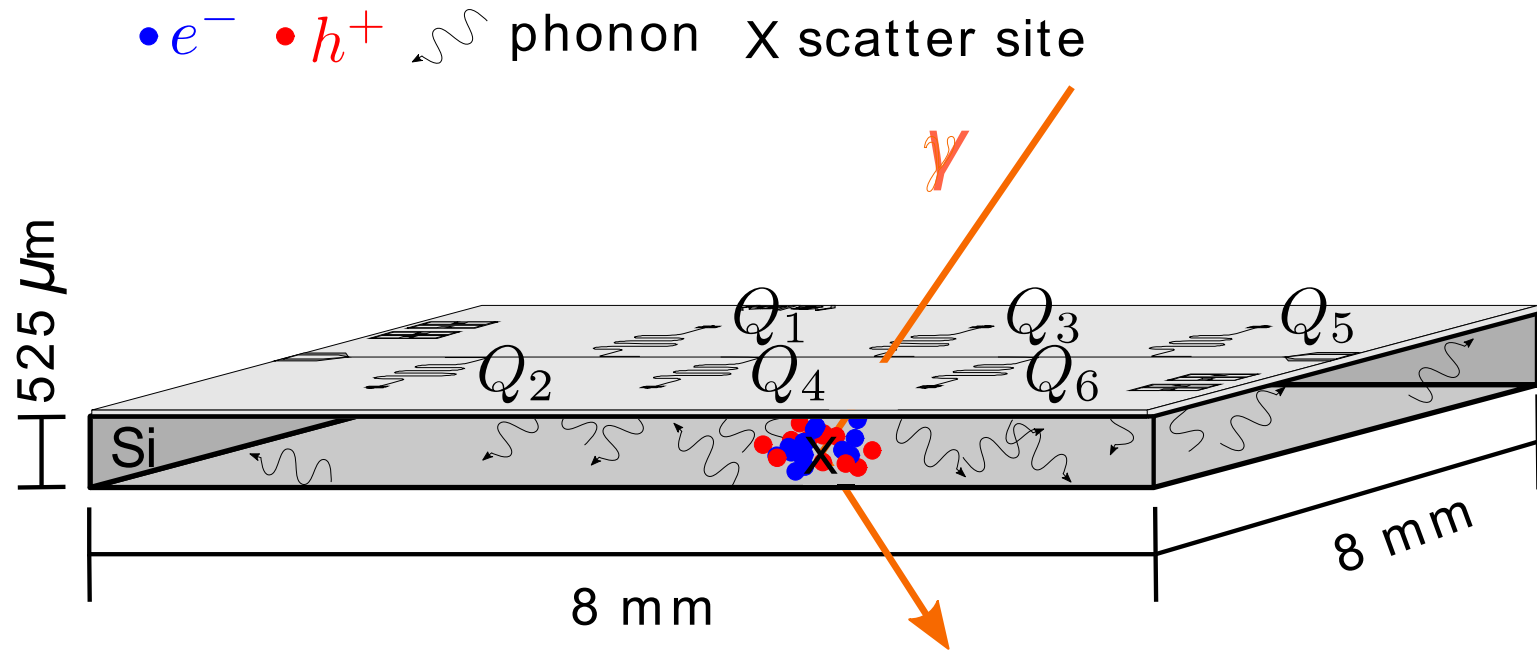
- Impact produces many electron-hole pairs that spread before trapping

Shifts in local charge environment for qubits near impact site

- Motion and recombination of e^- and h^+ radiates high-energy phonons; enhanced pair-breaking

Enhanced relaxation rates for qubits

Elevated QP charge-parity switching rates on qubits



Mitigating phonon-mediated QP poisoning

Possible mitigation strategies:

- SC gap-engineering to suppress tunneling of excess QPs
- Phonon downconversion...

Normal metal structures on back side of chip:

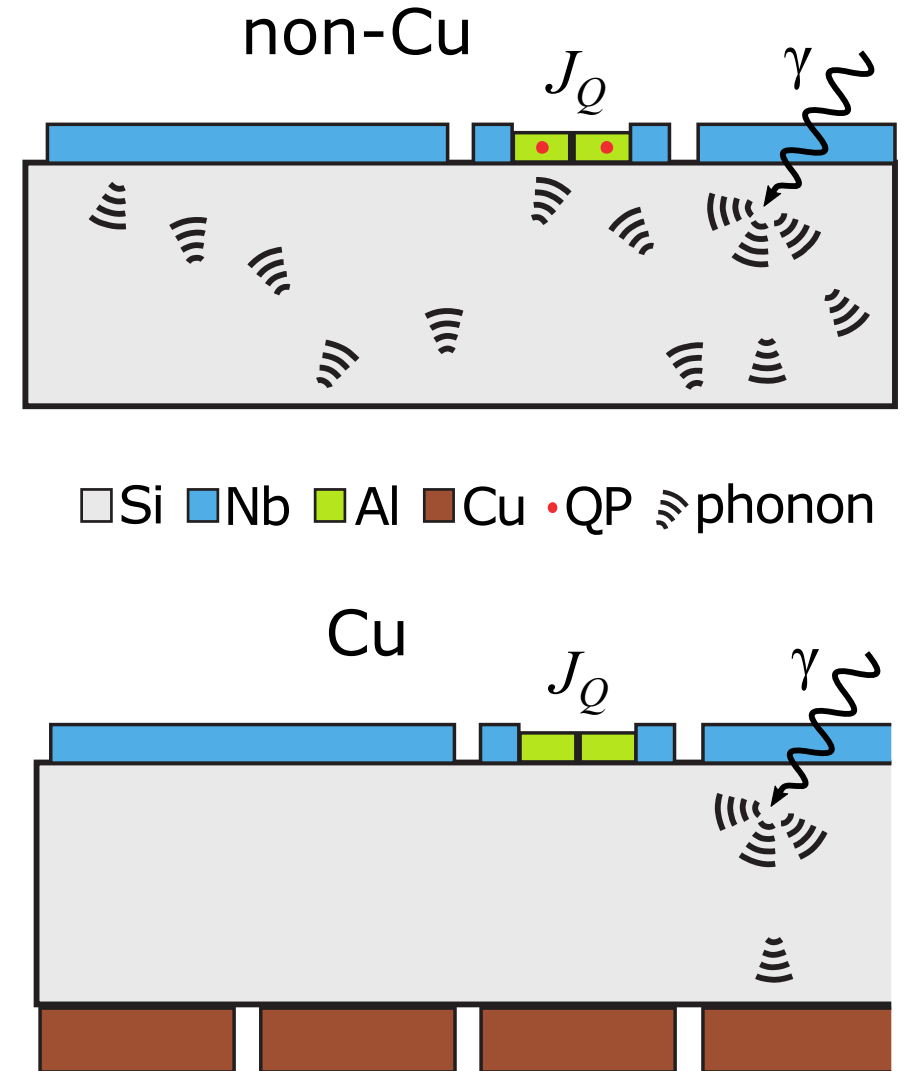
- Inelastic electron-phonon scattering
- Low e-ph interaction rate at low temperatures
- Need large metallic volume

Martinis, npj Quantum **7**, 1 (2021)

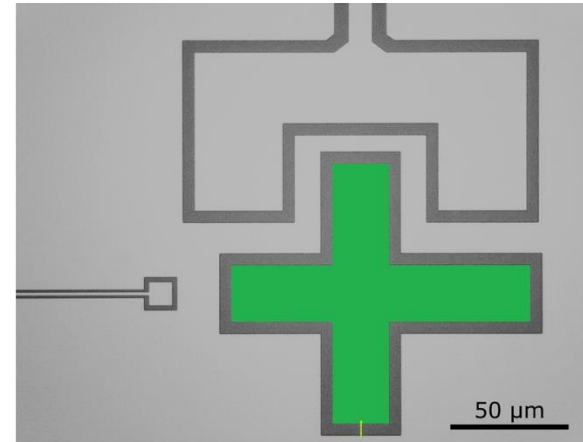
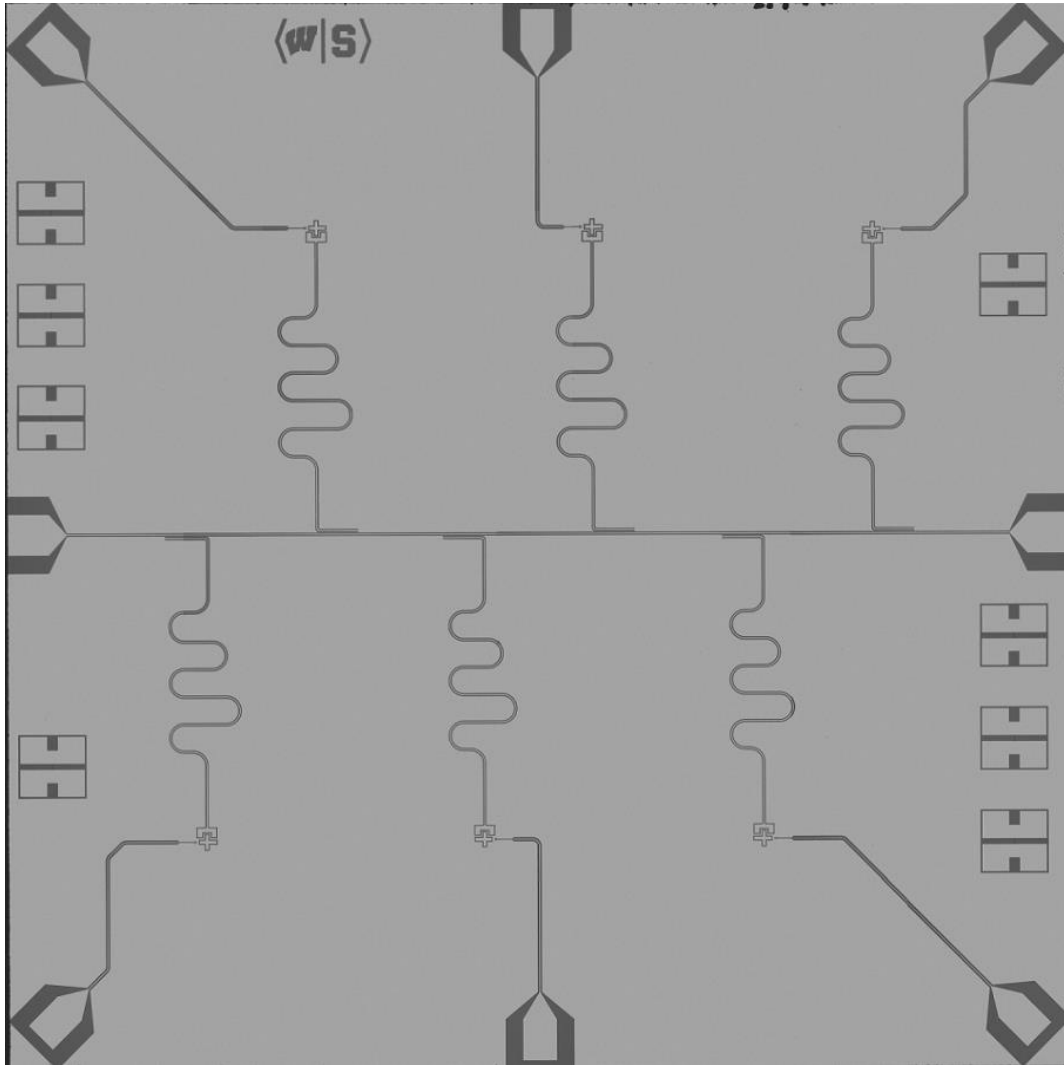
Alternatively, could use low-gap superconductor...

Henriques *et al.*, APL **115**, 212601 (2019)

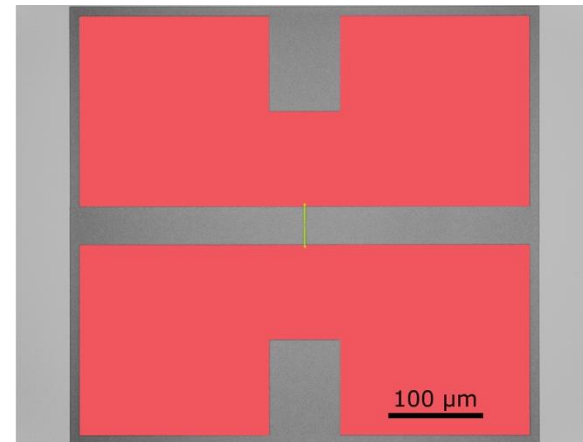
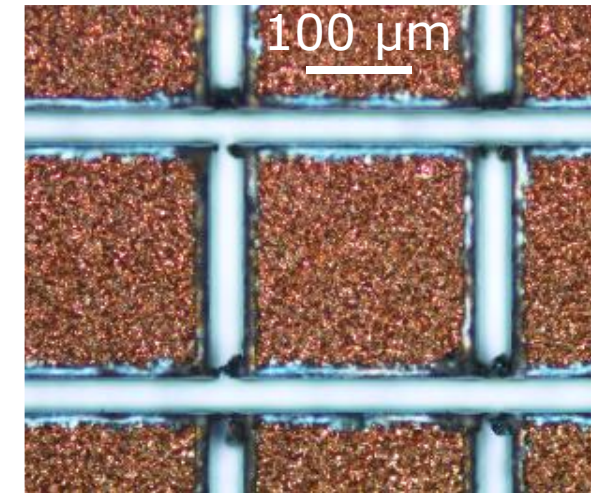
Karatsu *et al.*, APL **114**, 032601 (2019)



Device layout for studying phonon-mediated QP poisoning

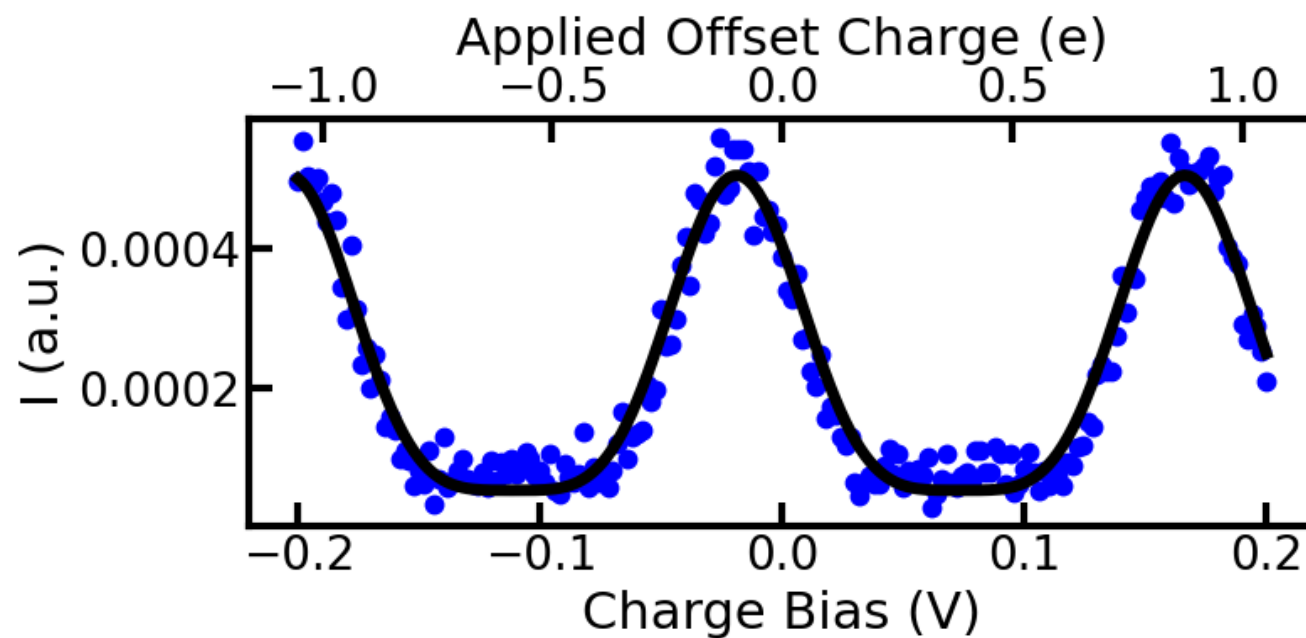
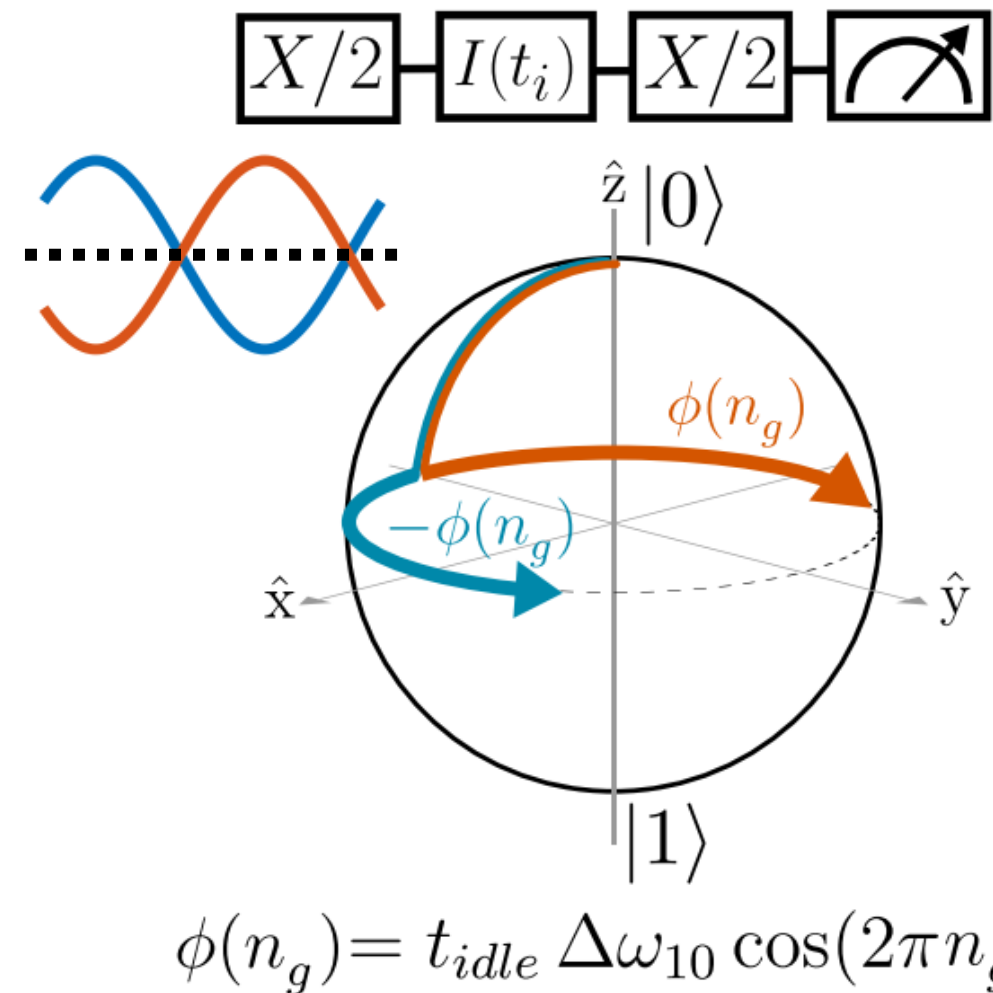


- Nb groundplane (or Al)
- Al/AlOx/Al junctions
- Charge-sensitive transmons



- Electroplated Cu
- Thickness: 1 μm , 10 μm

Using qubits as sensors of charge environment



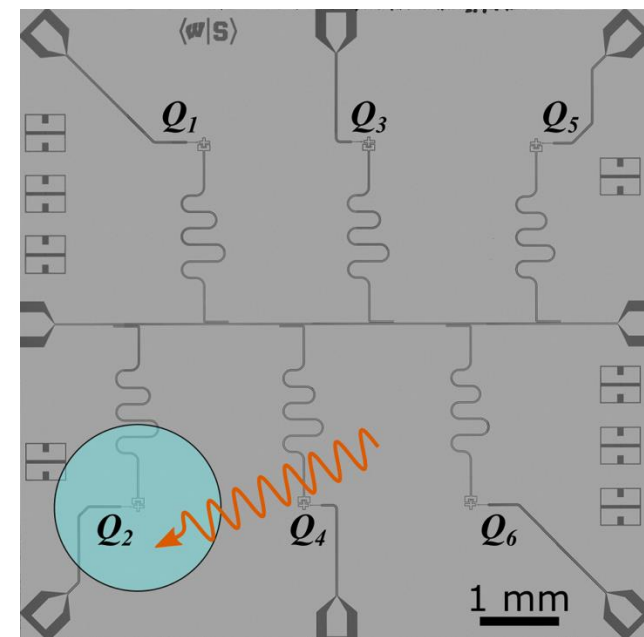
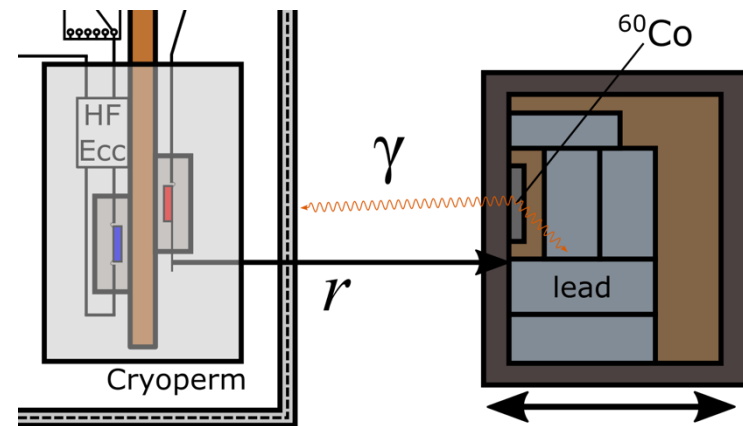
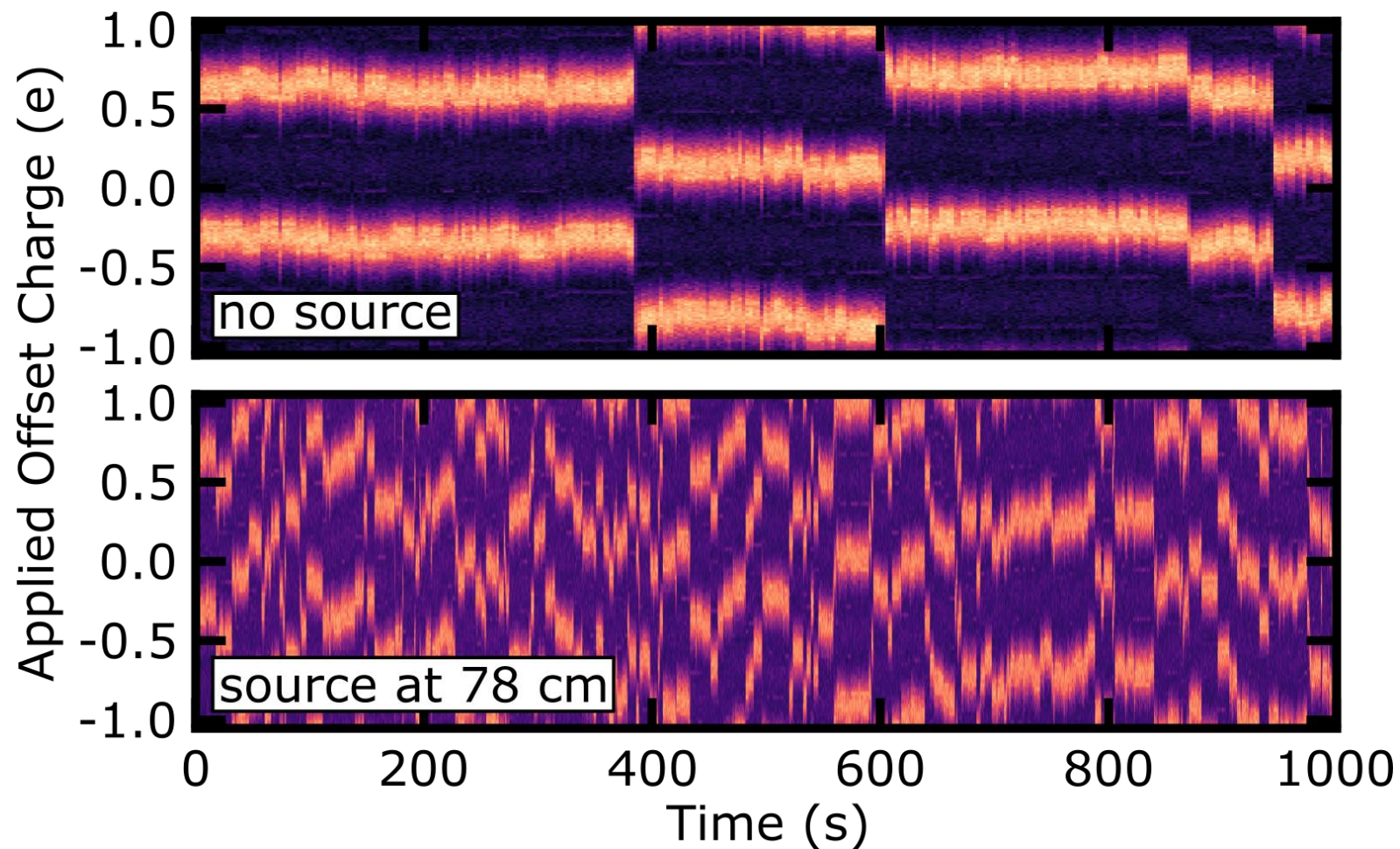
$$P_1 = \frac{1}{2} [d + v \cos(\pi \cos 2\pi n_g)]$$

$$n_g = n_g^{\text{ext}} + \delta n_g$$

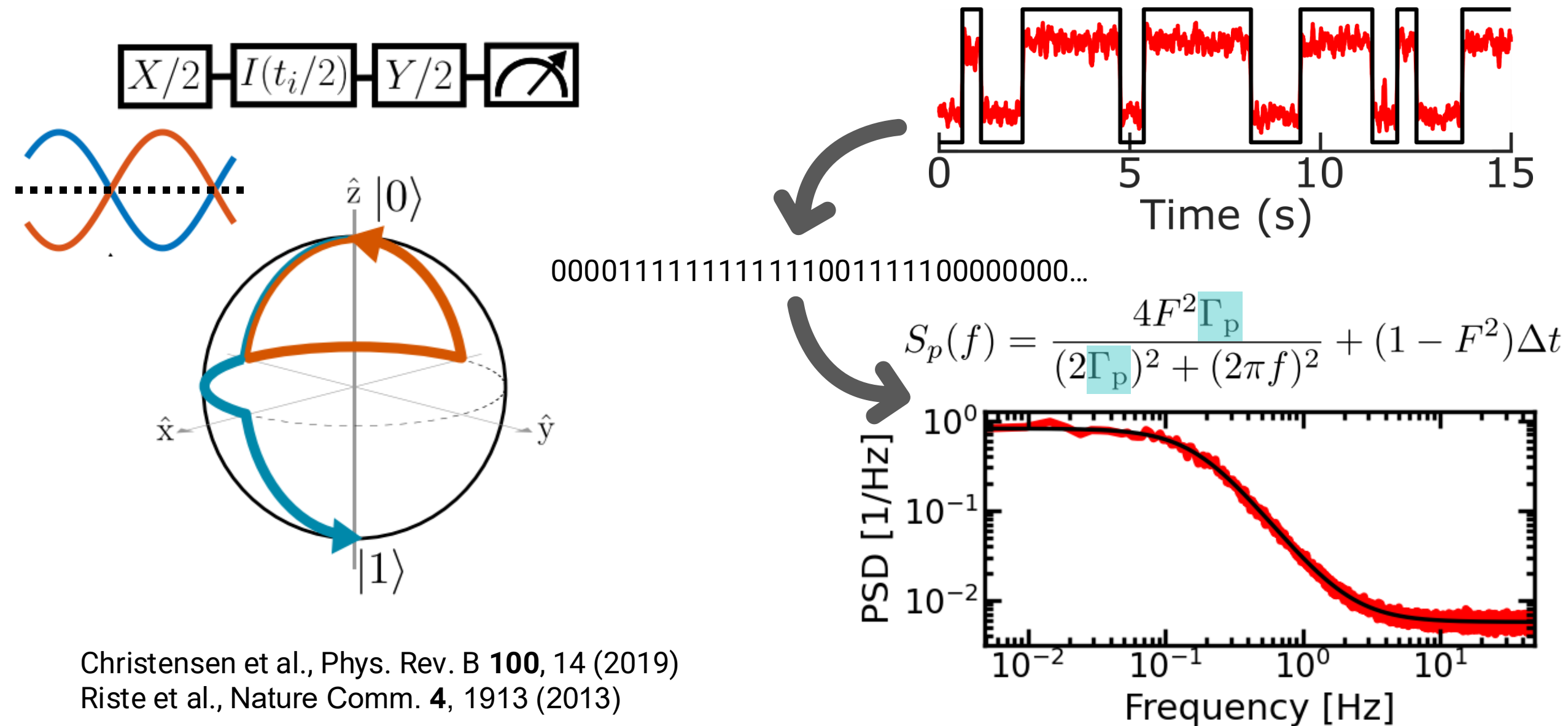
environmental

Dependence of offset-charge jump rate on γ dose

$$CT = -\left[X/2 - I(1/2\delta f) - X/2 \right] \rightarrow$$

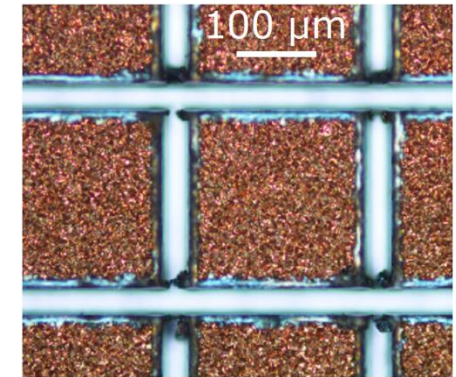
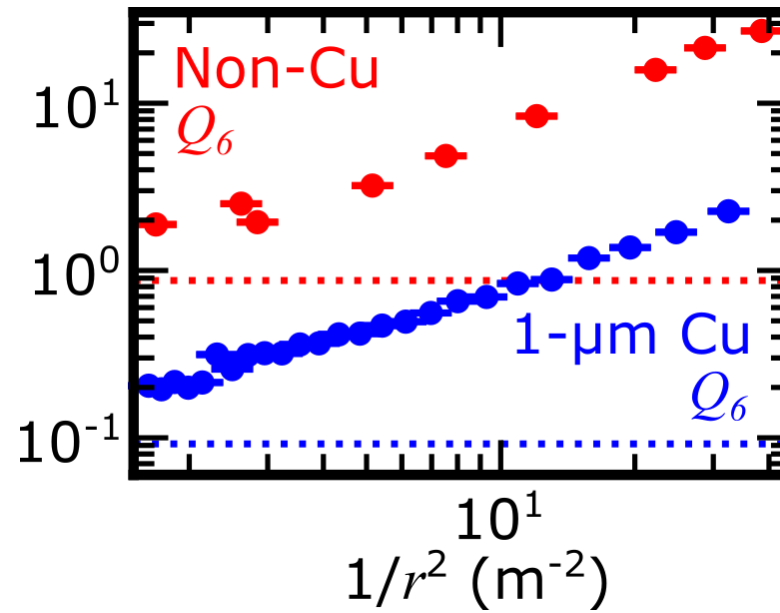
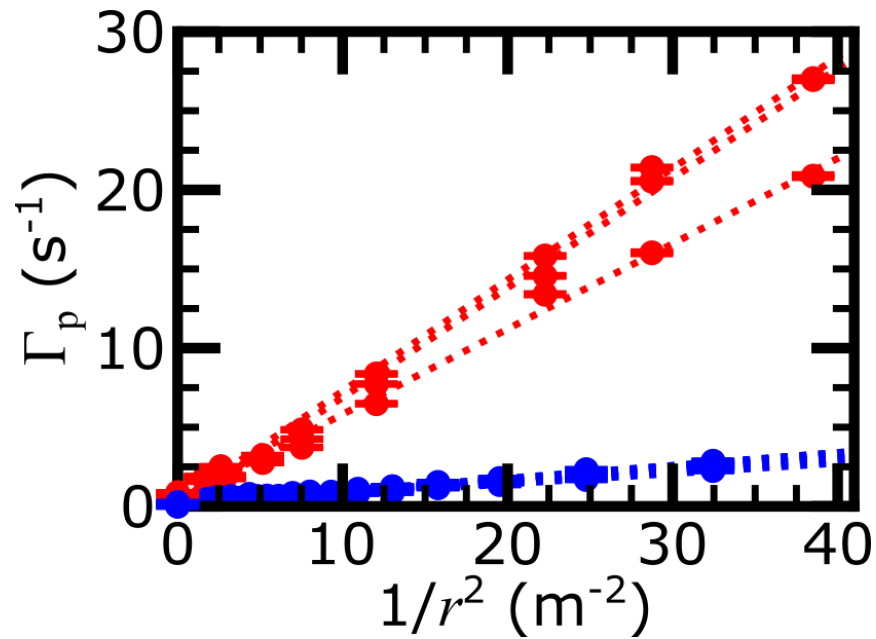


Sensing QP poisoning with charge-parity switching



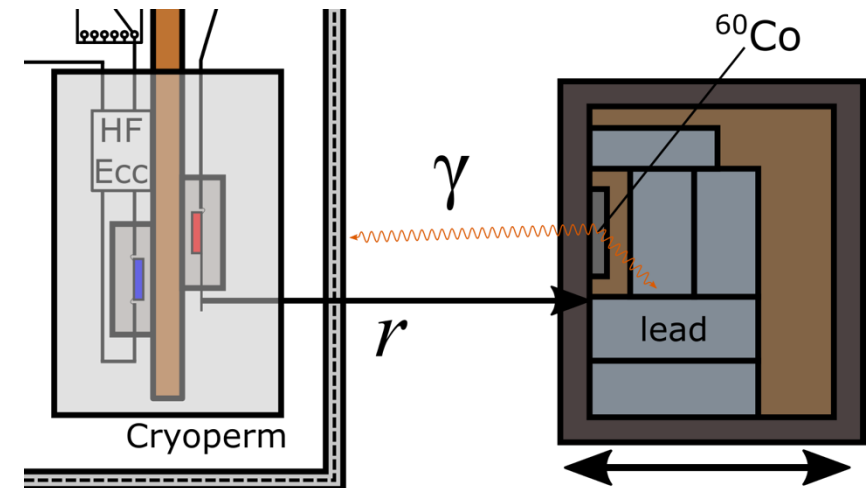
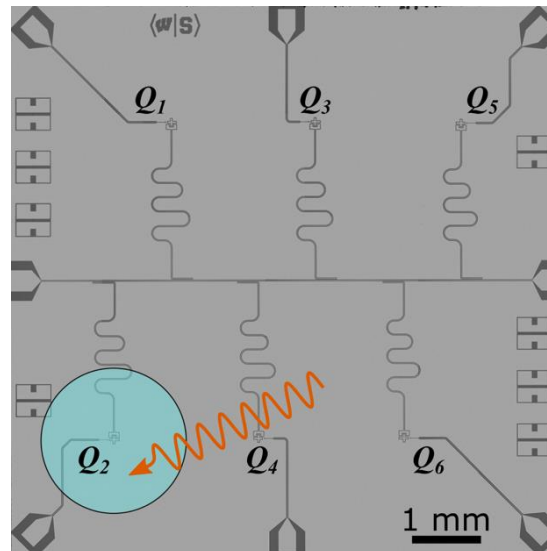
Christensen et al., Phys. Rev. B **100**, 14 (2019)
 Riste et al., Nature Comm. **4**, 1913 (2013)

Dependence of QP charge-parity switching rate on γ dose



- QP charge-parity switching rates proportional to $1/r^2$
- Rates suppressed by $\sim 10\times$ with 1- μm Cu islands

Larson *et al.*, PRX Quantum 6, 030339 (2025)

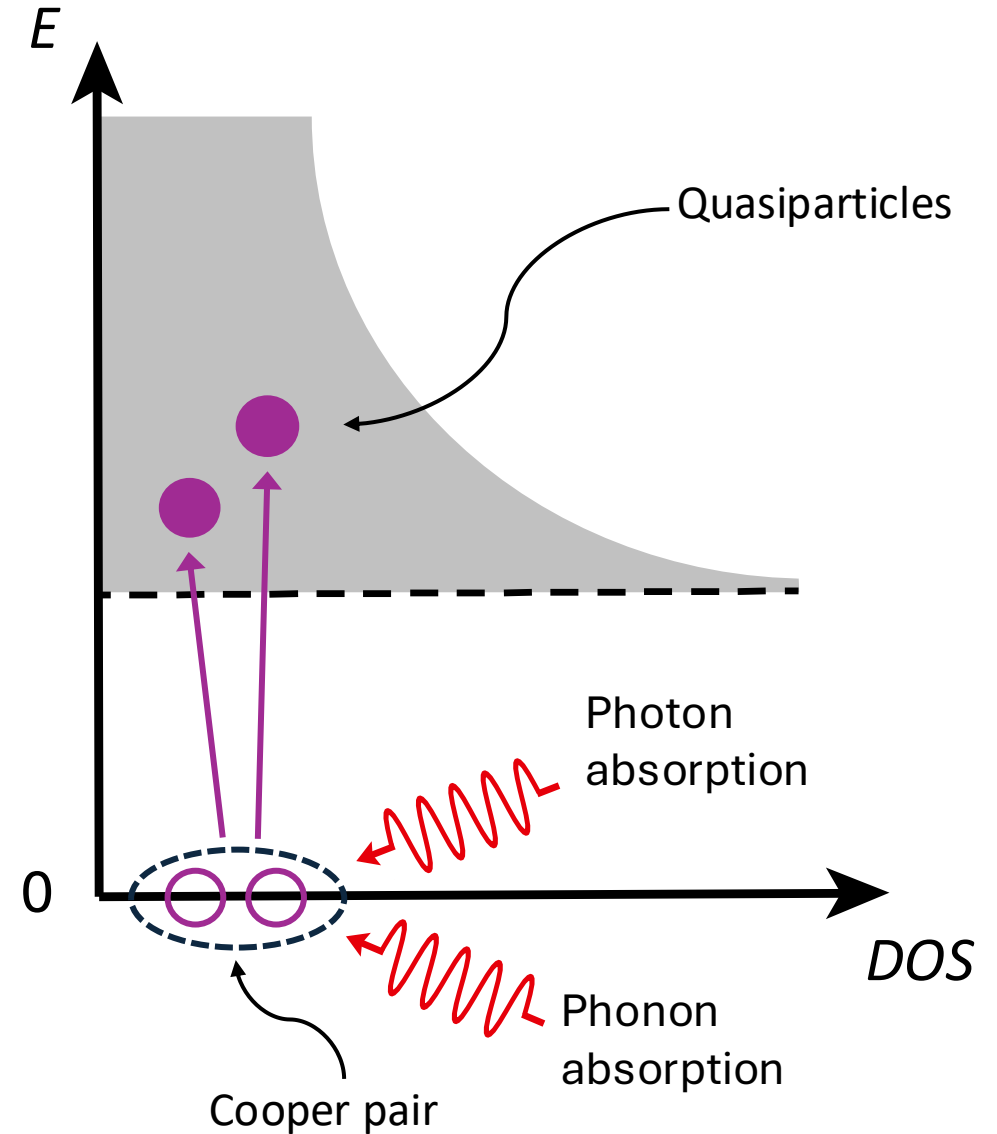


Generation of nonequilibrium QP in qubits

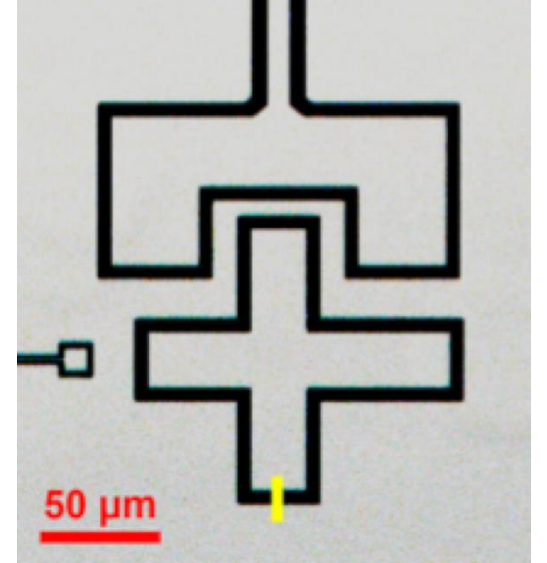
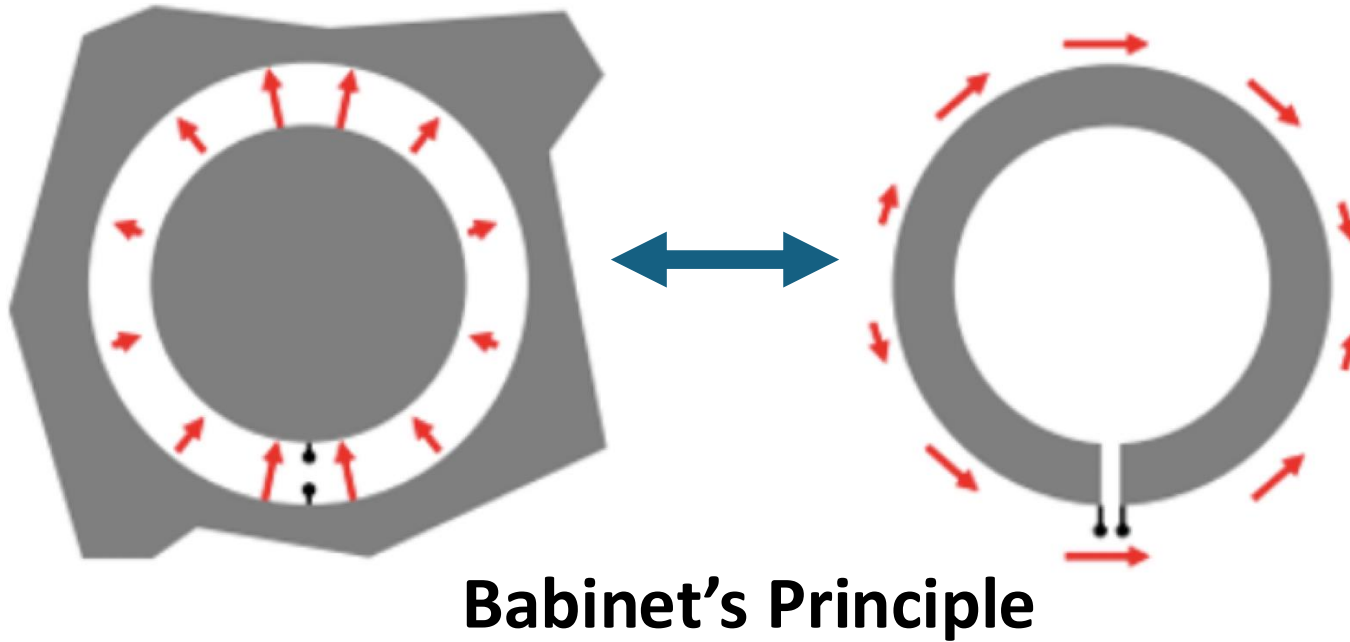
Deposition of pair-breaking energy generates QPs near qubit junction

- Impact of **phonons** near junction electrodes, e.g., following radiation impact
- Absorption of pair-breaking **photons**

Mechanism for photon absorption and coupling to qubit junction...?



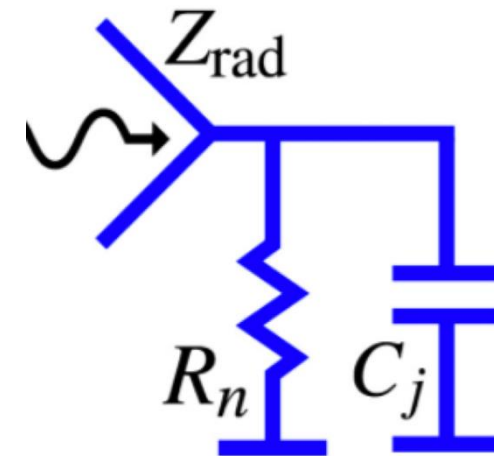
Spurious Antenna Modes of Superconducting Qubits



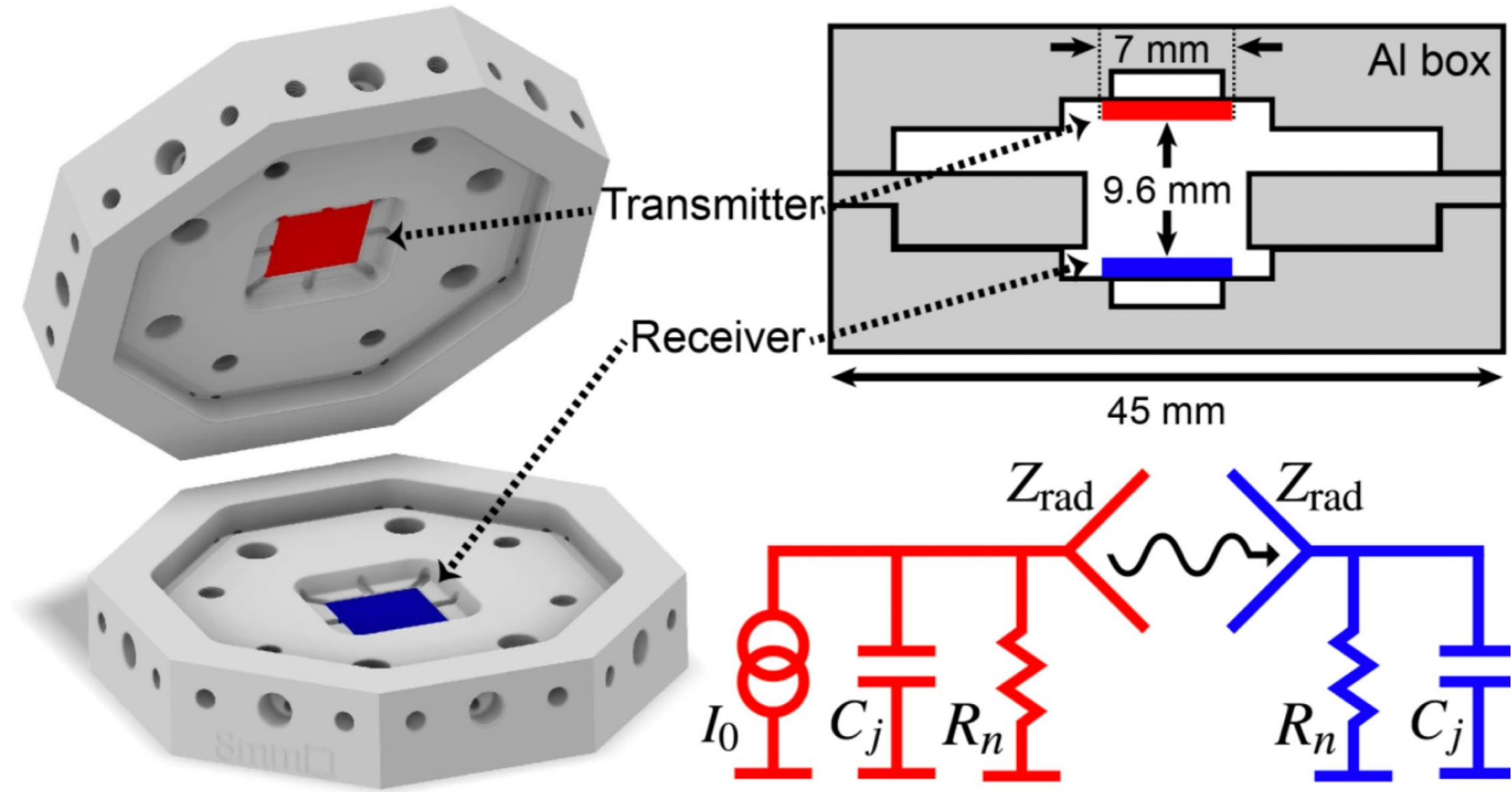
Coupling efficiency:

$$e_c = 1 - |\Gamma|^2$$

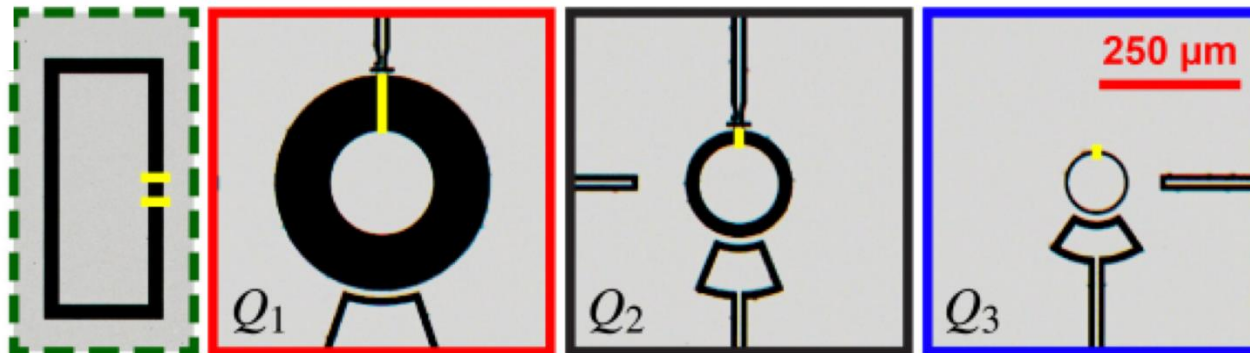
$$\Gamma = \frac{Z_{\text{rad}} - Z_J^*}{Z_{\text{rad}} + Z_J^*}$$



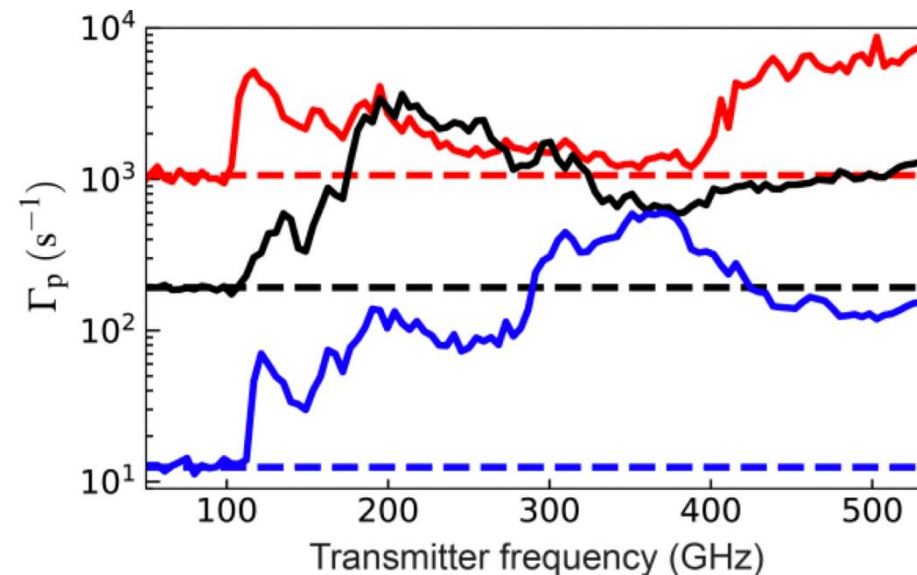
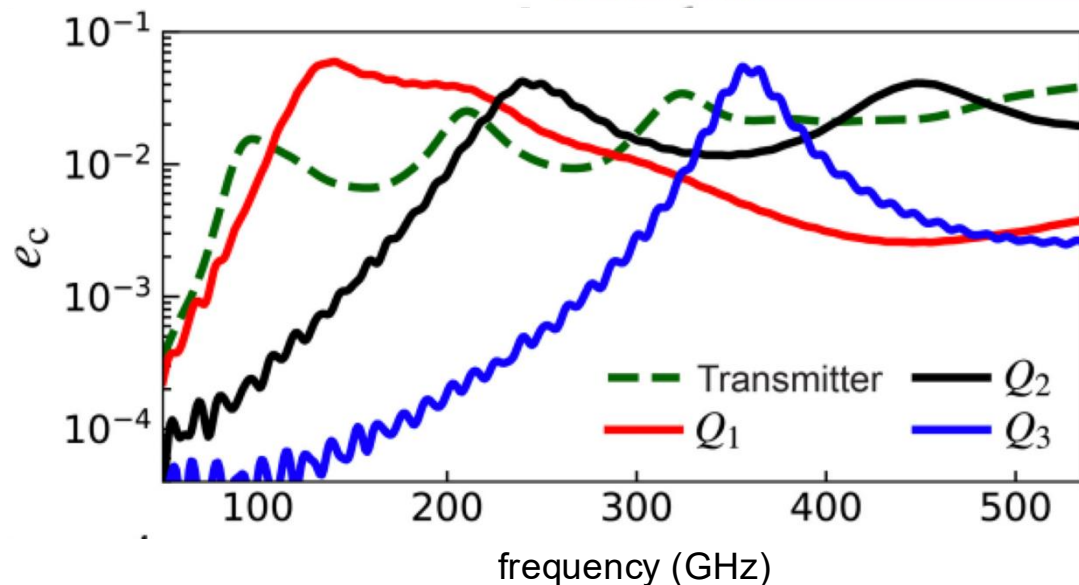
Measuring Photon-mediated Quasiparticle Poisoning



Photon-mediated Quasiparticle Poisoning



Liu *et al.*, Phys. Rev. Lett.
132, 017001 (2024)



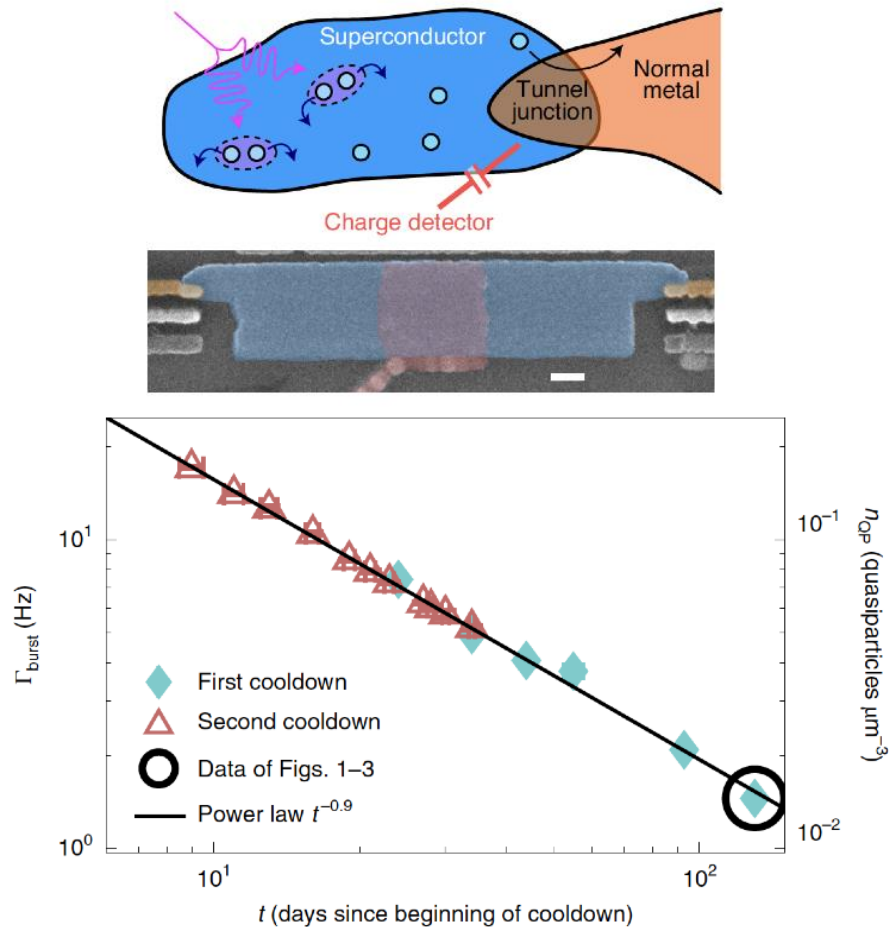
Mitigating photon-mediated QP poisoning:

- More compact shunt capacitor designs for higher frequency antenna modes
- Further improvements to filtering, shielding, thermalization to reduce effective blackbody temperature of photons in qubit environment

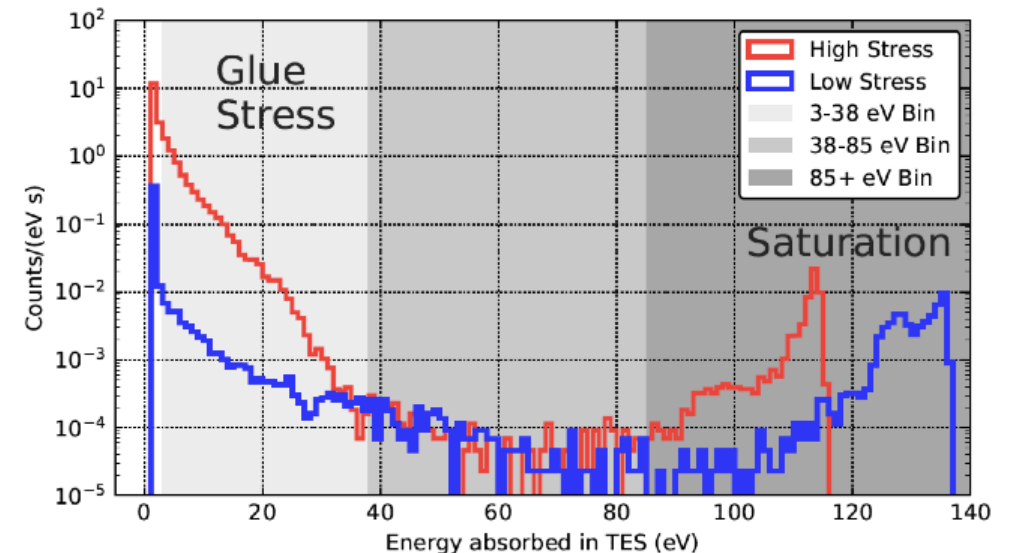
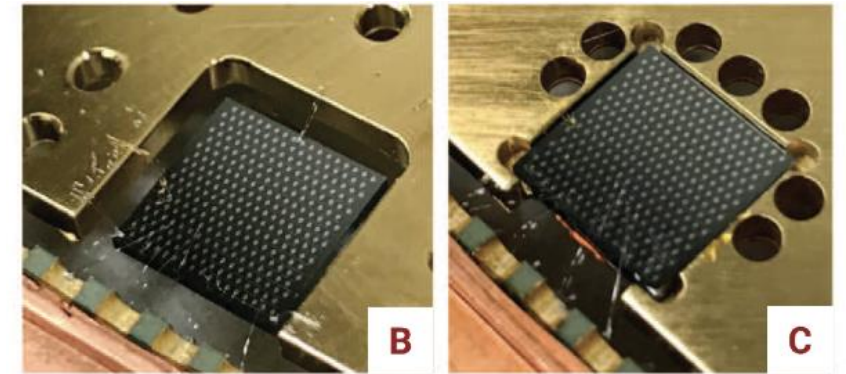
Correlated QP poisoning from phonon-only events

- Slow decrease in QP poisoning rates & low-energy excess events observed in TES detectors and mesoscopic SC devices

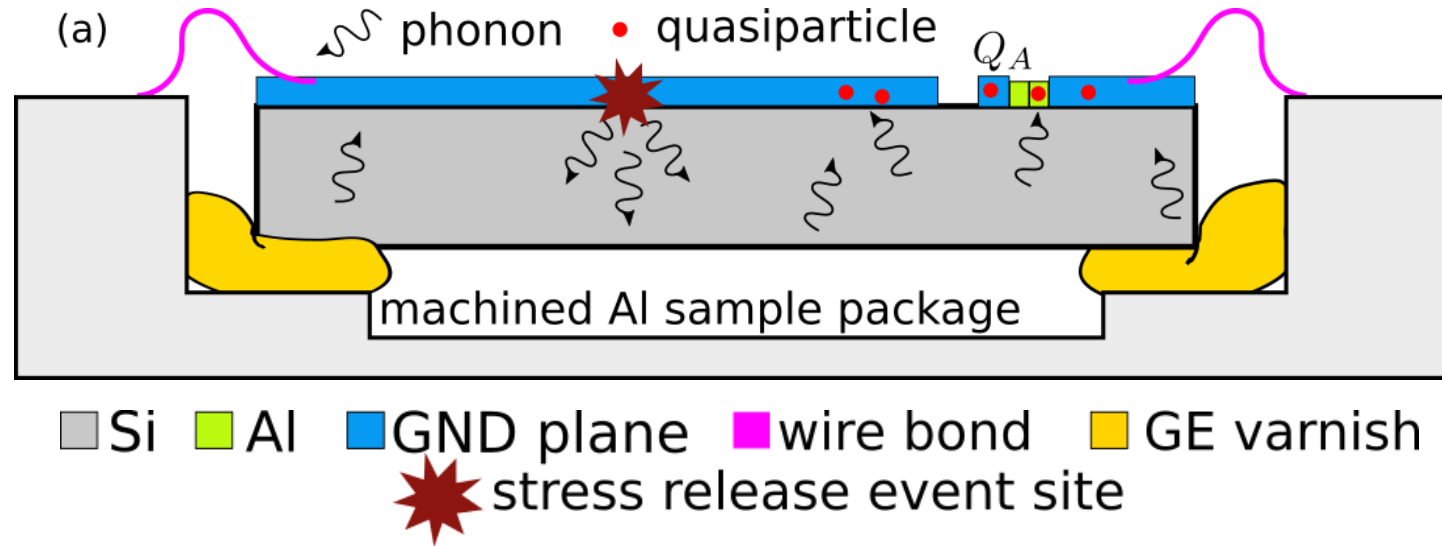
Mannila et al., Nature Phys 18, 145 (2022)



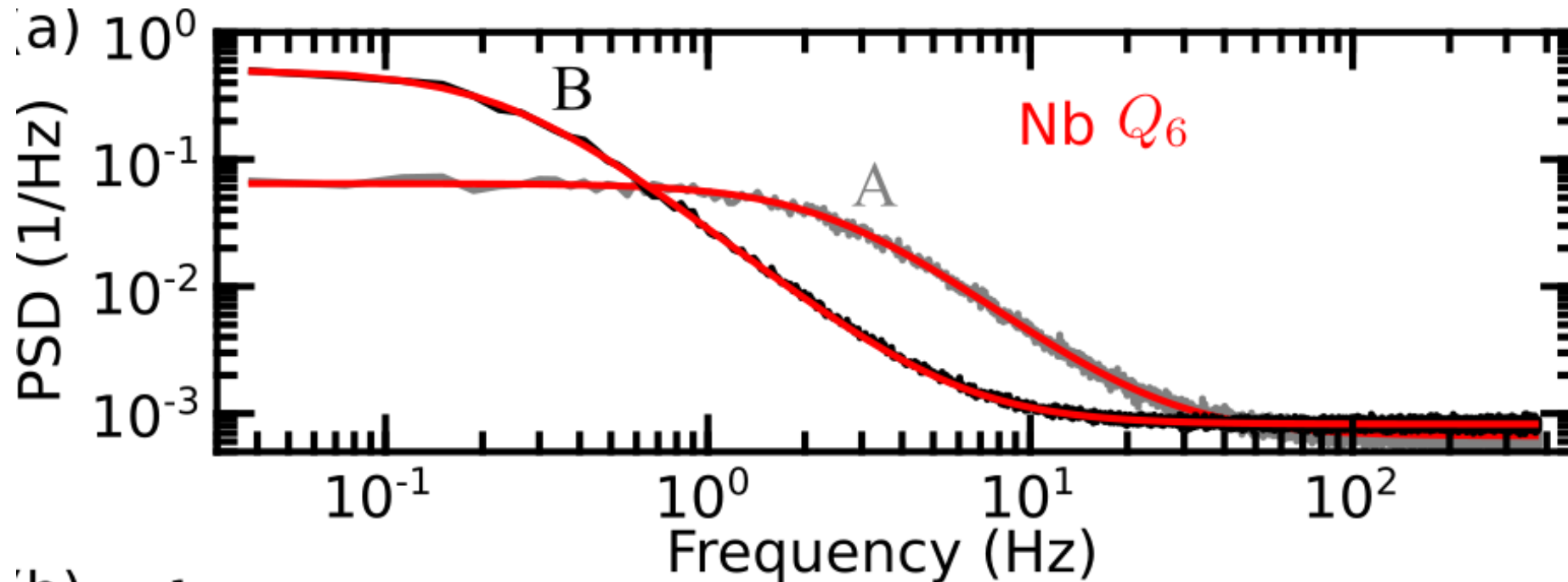
Anthony-Petersen et al., Nature Comm 15, 6444 (2024)



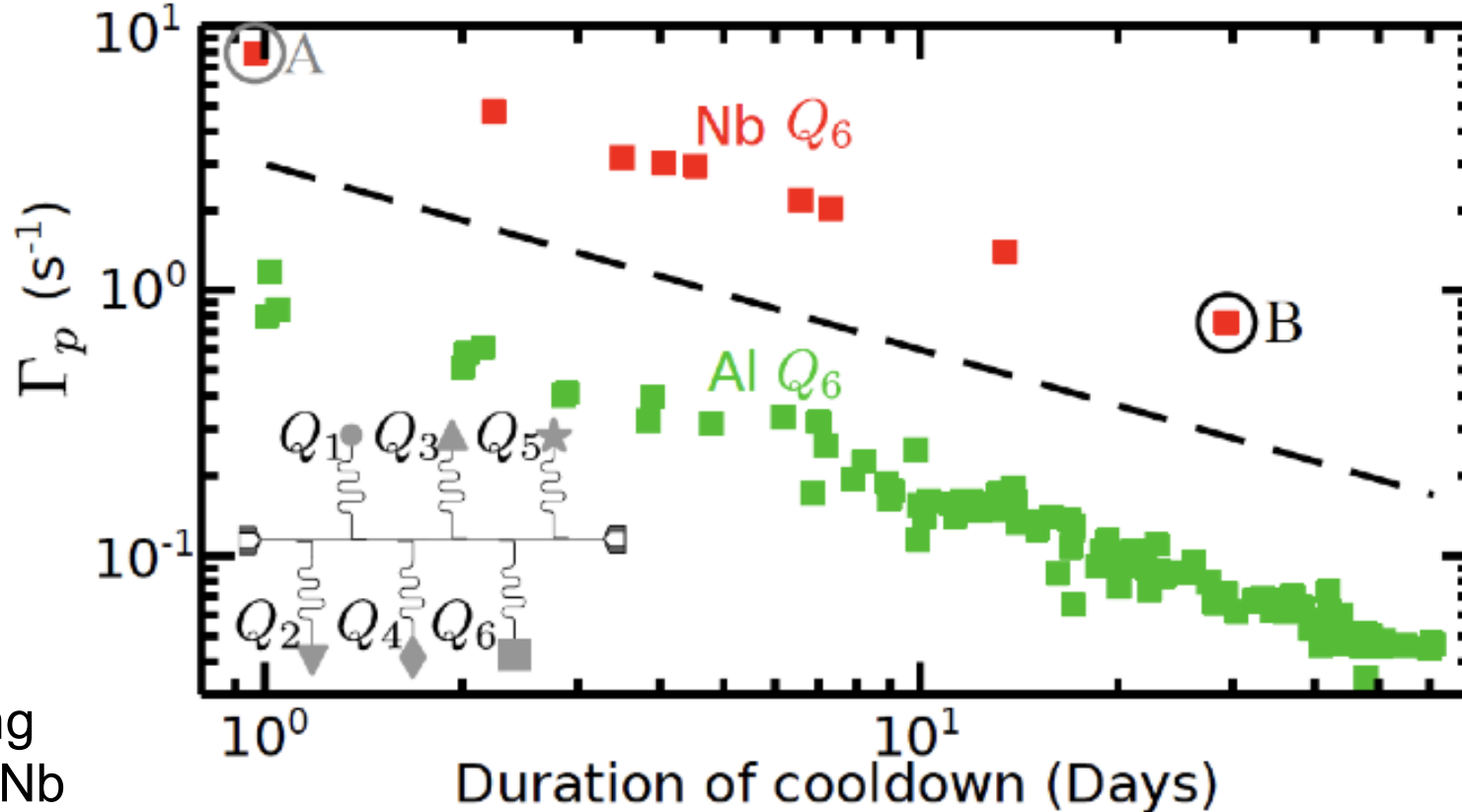
Correlated QP poisoning from phonon-only events



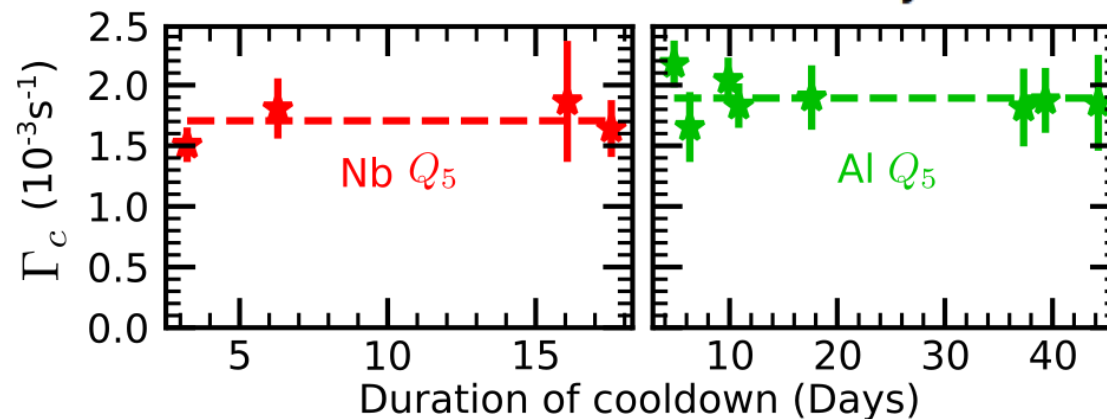
Yelton *et al.*, Phys. Rev. Lett. 135, 123601 (2025)



Reduction in charge-parity switching rates over time

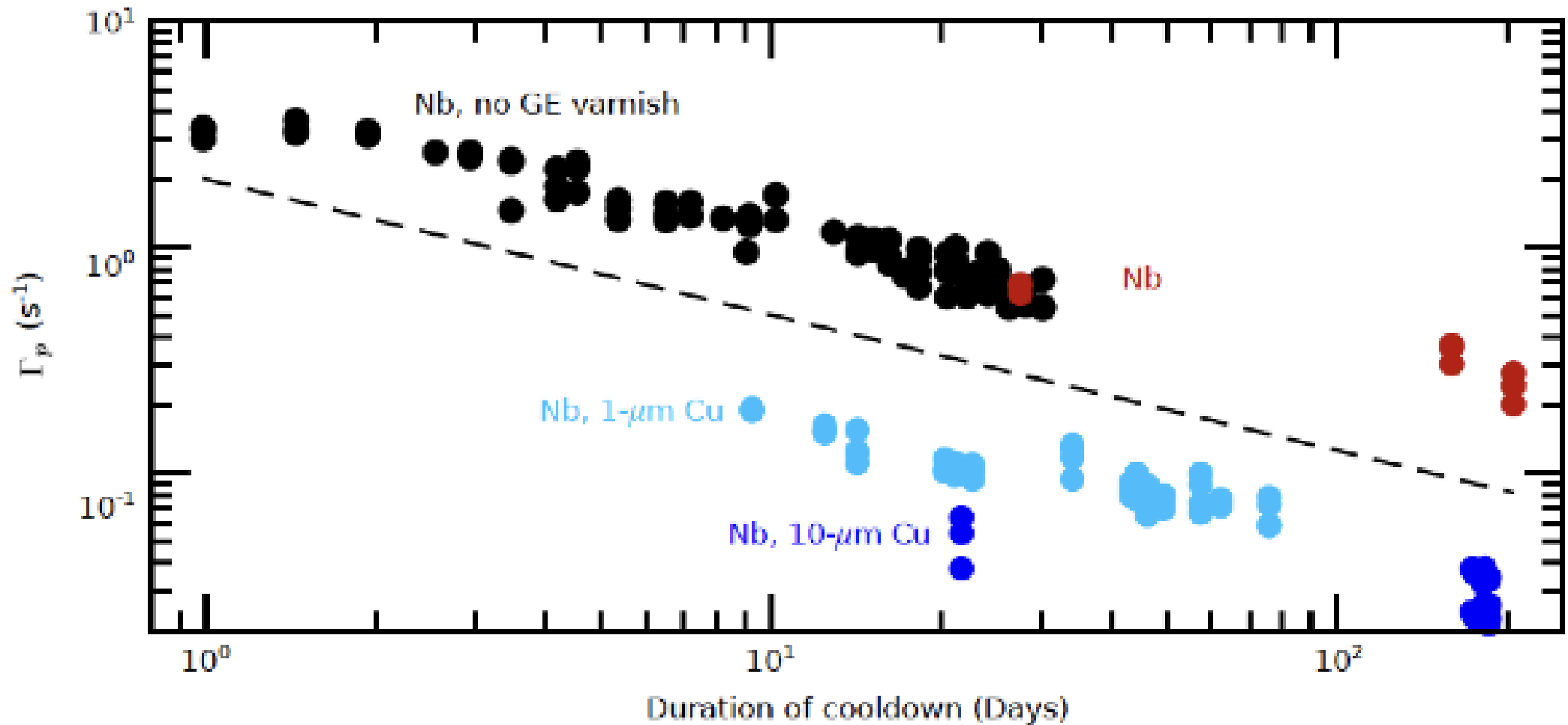


- Lower poisoning rates for Al vs. Nb compatible with phonon-mediated mechanism



*Offset-charge jump rate constant over course of cooldown

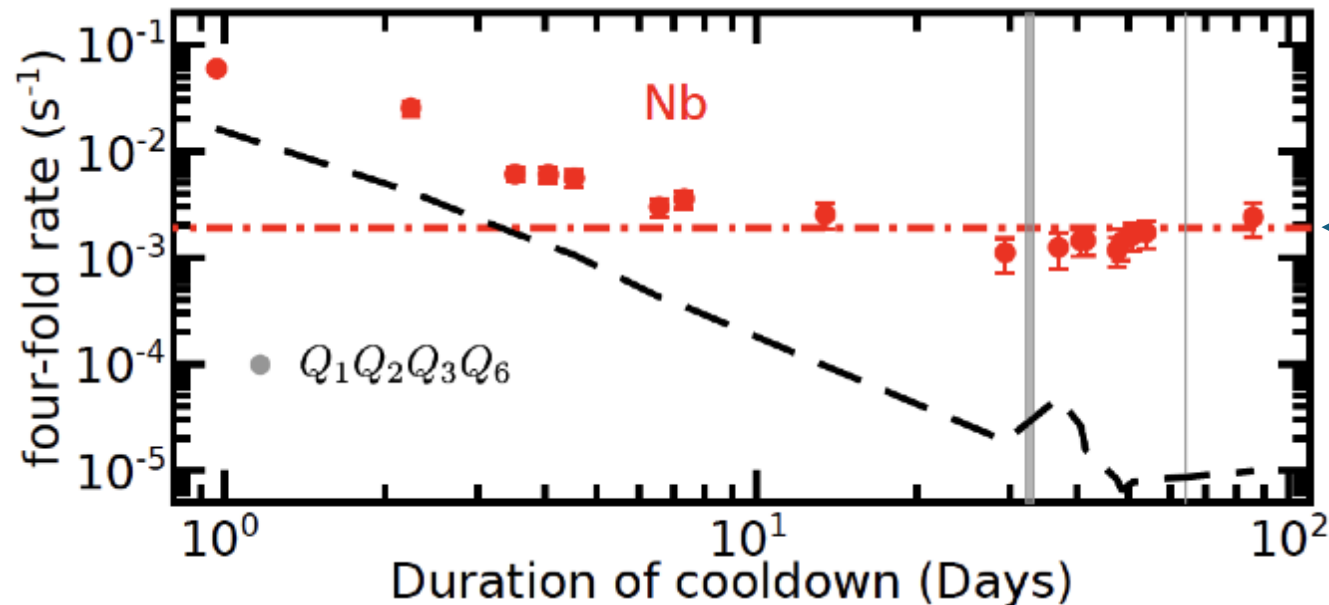
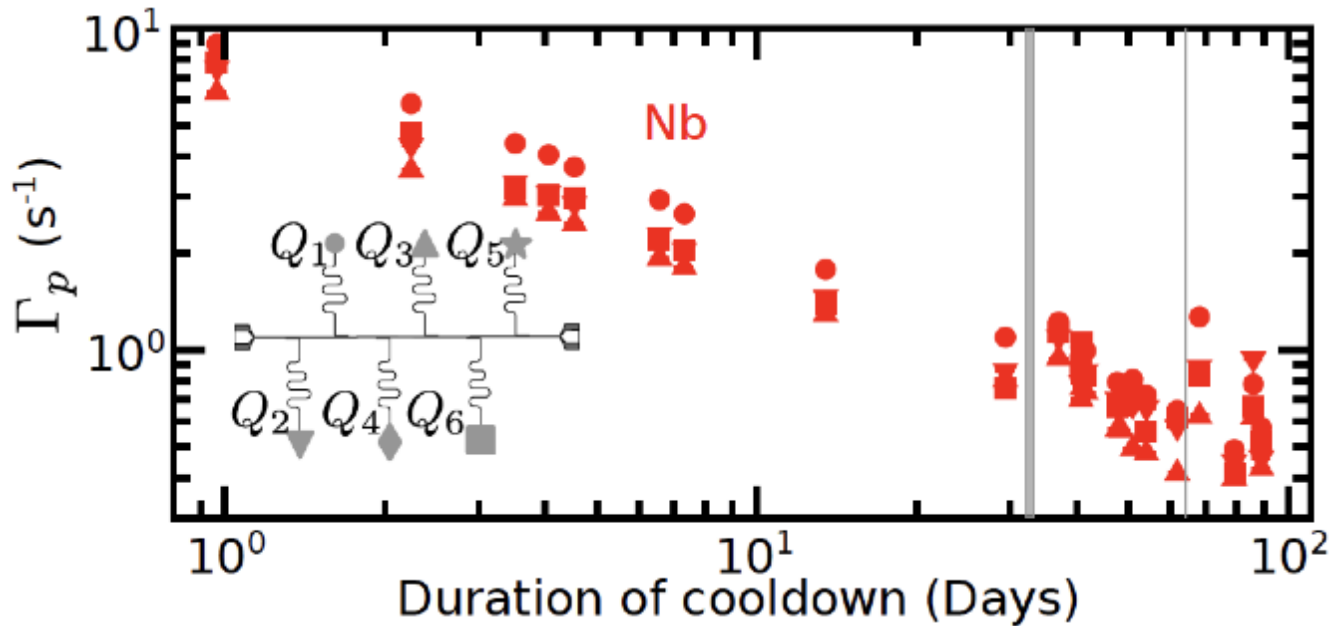
Reduction in charge-parity switching rates over time



- Lower poisoning rates with mitigation of pair-breaking phonons, but all configurations exhibit decreasing poisoning rates with time after start of cooldown

Reduction in *correlated* charge-parity switching rates over time

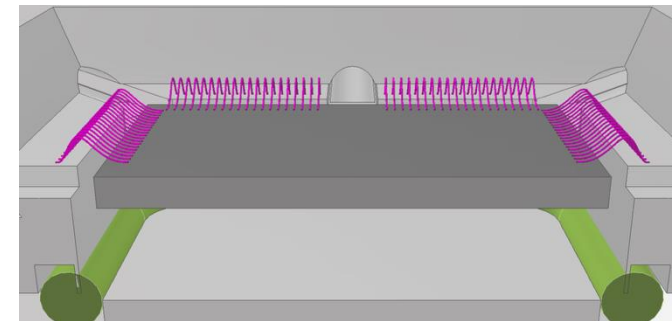
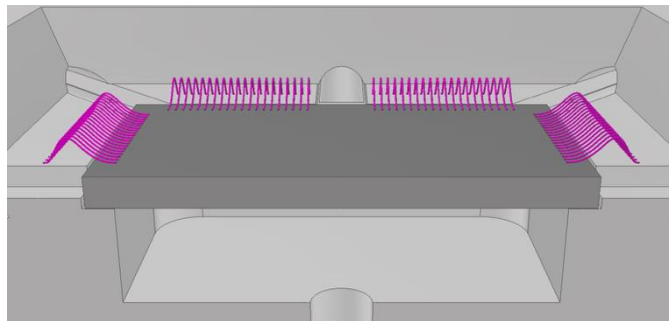
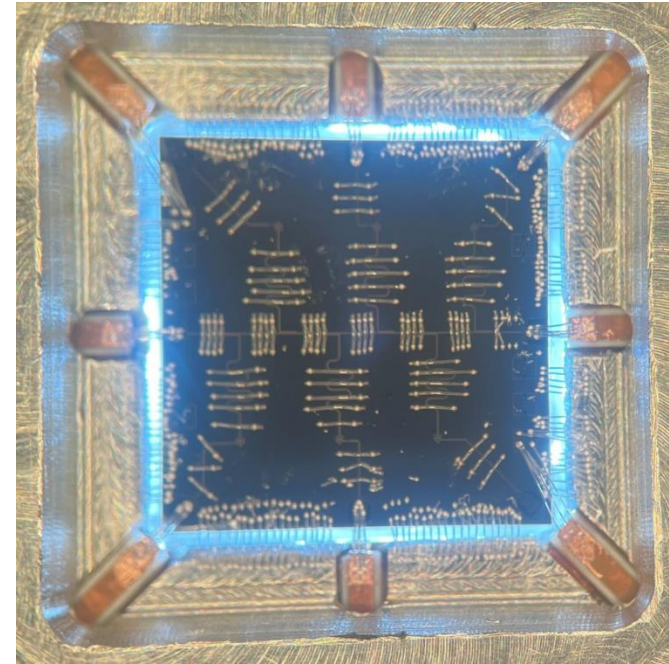
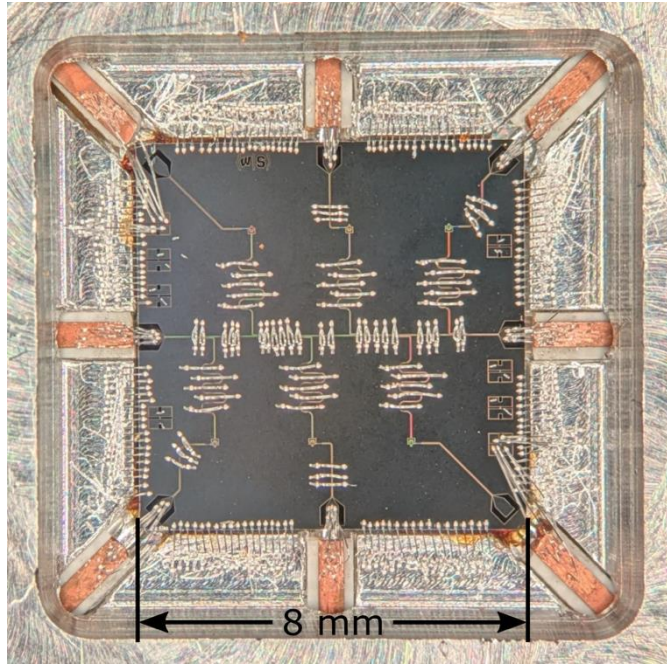
Yelton *et al.*, Phys. Rev. Lett. 135, 123601 (2025)



*Expected rate of 4-fold correlated poisoning due to γ impacts with no phonon mitigation = $2 \times 10^{-3} \text{ s}^{-1}$

- Correlations suggest phonon- rather than photon-mediated poisoning

Sample package with wirebond-suspension of chip



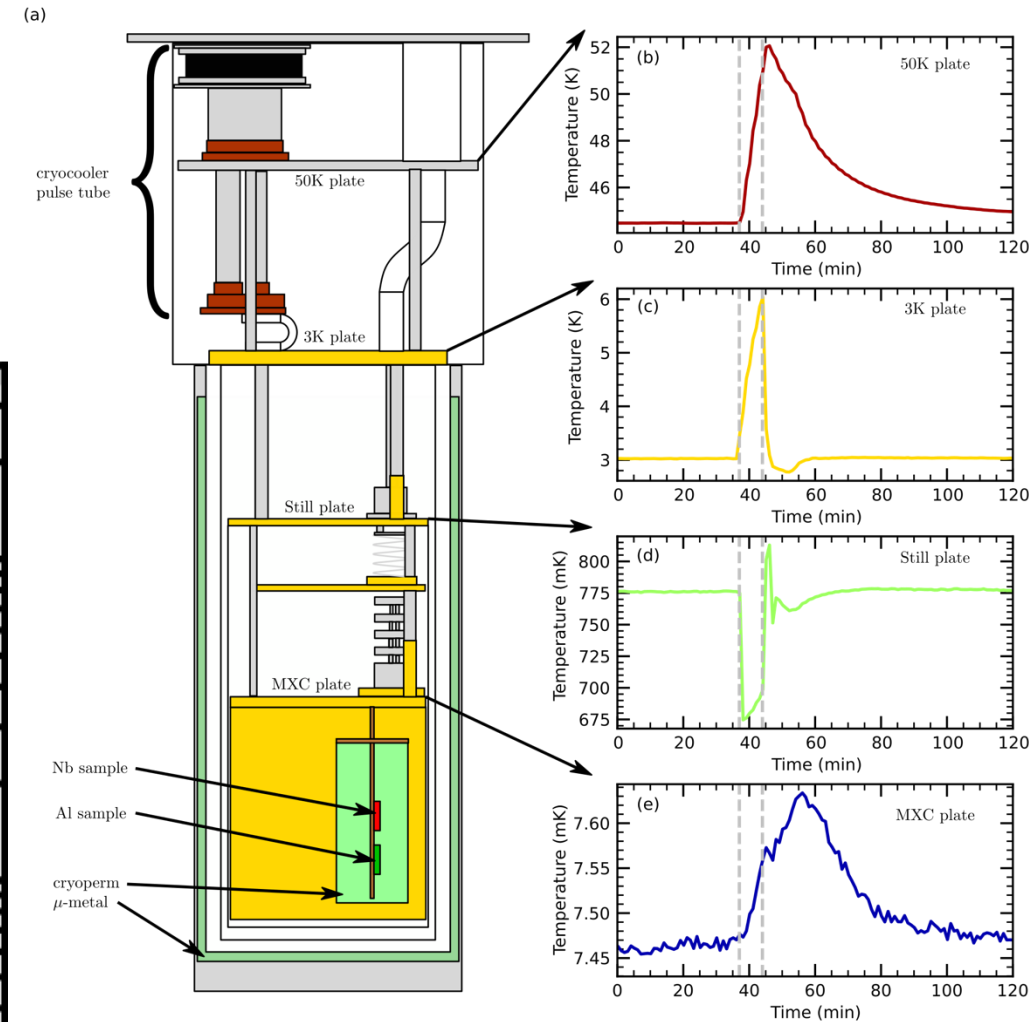
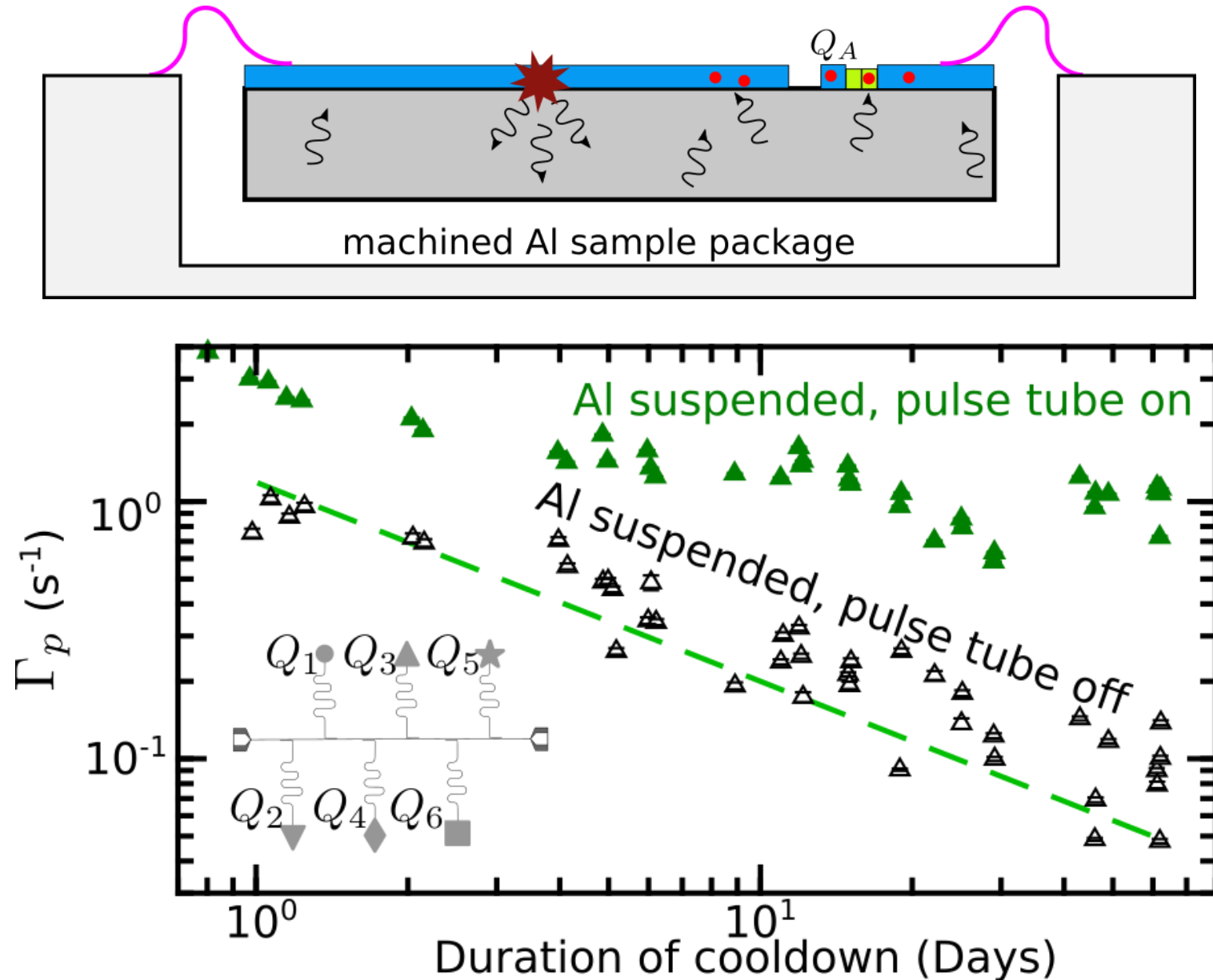
■ Si (chip)

■ Al (sample box)

■ Al (wire bond)

■ In wire

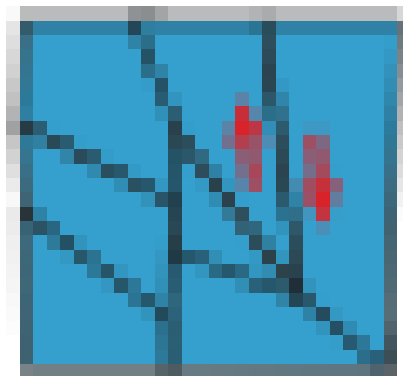
QP charge-parity switching rates with wirebond-suspension of chip



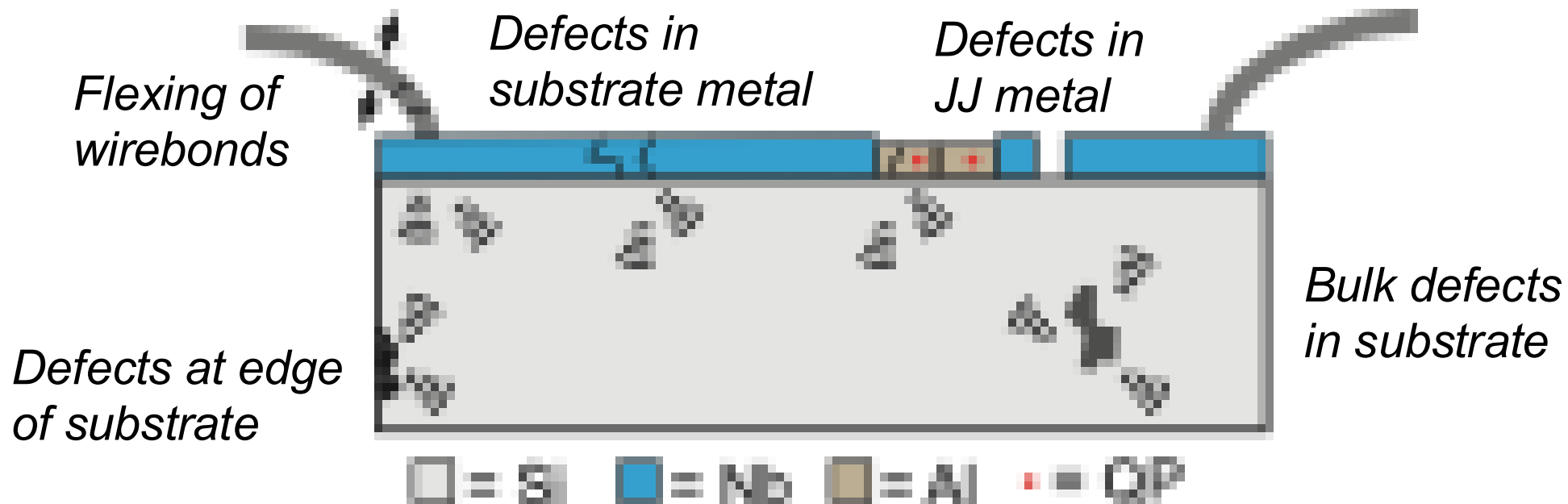
Yelton *et al.*, Phys. Rev. Lett.
135, 123601 (2025)

Potential sources of phonon-only events

Stick-slip relaxation
of built-up stresses

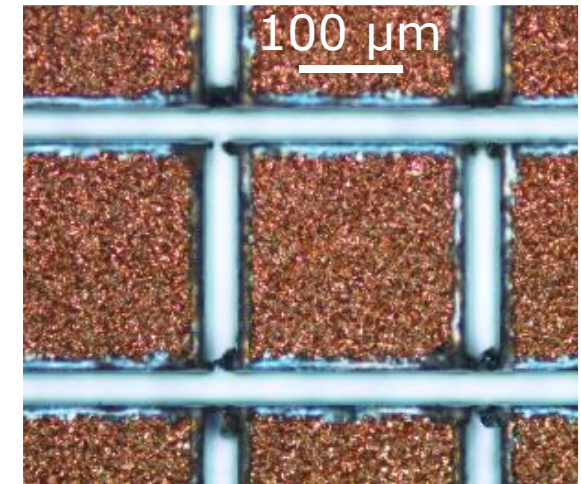
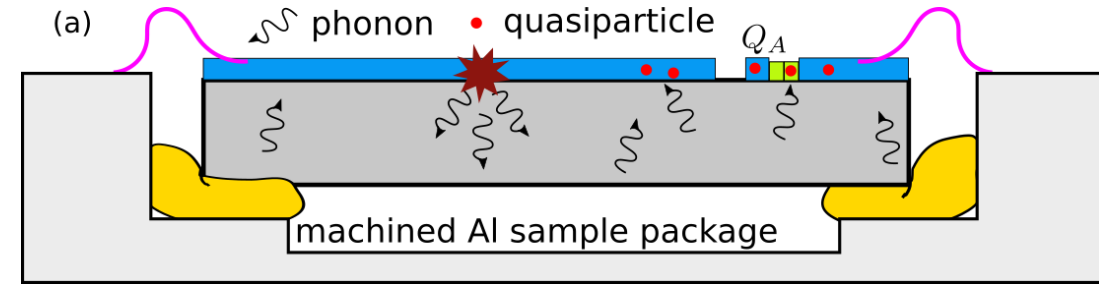


Releases burst of
pair-breaking
phonons



Conclusions & Ongoing Work

- Compact qubit designs plus extensive IR shielding and filtering can suppress photon-mediated QP poisoning
- Phonon-only events produce QP poisoning without accompanying charge signal
- Releases of built-up mechanical stresses in device produce bursts of pair-breaking phonons
- Rate of phonon bursts decreases gradually with time after start of cooldown



Iaia, Ku *et al.*, Nature Comm.
13, 6425 (2022)

Yelton *et al.*, Phys. Rev. B
110, 024519 (2024)

Larson *et al.*, PRX Quantum 6, 030339 (2025)

Yelton *et al.*, Phys. Rev. Lett. 135, 123601 (2025)

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